



XRF-Spectrometer

LXRF-A10

XRF-SPECTROMETER LXRF-A10

XRF-Spectrometer LXRF-A10 is a microprocessor controlled high-count throughput unit with low detection limits for wide range of elements. Provision of multi-elemental analysis with detection limits upto 1 ppm. Built-in movable platform for easy location of testing point. High resolution detector improves analysis accuracy. Equipped with safety features of optical tube shielding with no X-ray radiation and high voltage emergency locking.

Features

- Detection limit – 1 ppm
- Measureable elements – S to U
- Elemental content – 1 ppm to 99 %
- Movable sample platform for easy detection of testing point
- Built-in electric cooling Si-PIN detector
- Safety features - optical tube shielding with no X-ray radiation and high voltage emergency locking

Applications

Used in detection of plating thickness of metals, concentration of plating solution , RoHS detection and analysis, full-element analysis and electro plating industries

Specifications

Model No.	LRXF-A10
Measureable elements	S to U
Detection limit	1 ppm
Temperature	15 ~ 30 °C
Elemental content	1 ppm to 99 %
Repeatability	0.1 %
Stability	0.1 %
Power supply	AC 220 V ± 5 V
Dimensions	550 x 410 x 320 mm
Weight	45 kg